

# ATOMIC FORCE MICROSCOPY (AFM)

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MANUFACTURER : NanoINK

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MODEL : Nscriptor

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## Samples

- Samples sizes: Maximum 50 mm
- Thickness: Maximum 38 mm

## Analysis

- Types : contact mode and AC (tapping) mode
- Applications: measurements of the size of particle on a surface, film thickness and surface roughness

## Characteristics

- Mapping possible with a precision of 150 nm
- Lateral resolution: 1 nm
- XYZ scanner range: 90 x 90 x 8  $\mu\text{m}$
- Equipment that allows Dip-Pen Nanolithography